Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/722,634	OZAKI, ICHIRO	
Examiner	Art Unit	_
JOHN J. LEE	2618	

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SEARCHED									
Class Subclass		Date	Examiner						
455	413 414.1 414.3 414.3 415.1 556.1 556.1	12/20/2006	J.L <sup>.</sup>						
709	207	12/20/2006	J.L						
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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